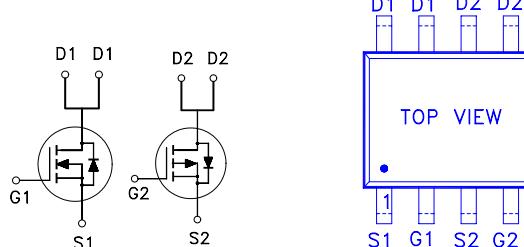


**NIKO-SEM**
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**PRODUCT SUMMARY**

	$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
N-Channel	30	21mΩ	7A
P-Channel	-30	35mΩ	-6A


 G : GATE  
 D : DRAIN  
 S : SOURCE
**ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	N-Channel	P-Channel	UNITS
Drain-Source Voltage	$V_{DS}$	30	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	$\pm 20$	V
Continuous Drain Current	$I_D$	7	-6	A
		6	-5	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	28	-24	
Power Dissipation	$P_D$	2	1.3	W
Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150		$^\circ\text{C}$
Lead Temperature ( $1/16$ " from case for 10 sec.)	$T_L$	275		

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		62.5	$^\circ\text{C} / \text{W}$

<sup>1</sup>Pulse width limited by maximum junction temperature.<sup>2</sup>Duty cycle  $\leq 1\%$ **ELECTRICAL CHARACTERISTICS ( $T_C = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu\text{A}$	N-Ch	30		V
		$V_{GS} = 0V, I_D = -250\mu\text{A}$	P-Ch	-30		
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	N-Ch	0.8	1.5	2.5
		$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	P-Ch	-0.8	-1.5	-2.5

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Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0V, V_{GS} = \pm 20V$	N-Ch			$\pm 100$	nA
		$V_{DS} = 0V, V_{GS} = \pm 20V$	P-Ch			$\pm 100$	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 24V, V_{GS} = 0V$	N-Ch			1	$\mu A$
		$V_{DS} = -24V, V_{GS} = 0V$	P-Ch			-1	
		$V_{DS} = 20V, V_{GS} = 0V, T_J = 55^\circ C$	N-Ch			10	$\mu A$
		$V_{DS} = -20V, V_{GS} = 0V, T_J = 55^\circ C$	P-Ch			-10	
		$V_{DS} = 5V, V_{GS} = 10V$	N-Ch	28			A
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = -5V, V_{GS} = -10V$	P-Ch	-24			
		$V_{GS} = 4.5V, I_D = 6A$	N-Ch		21	32	$m\Omega$
Drain-Source Resistance <sup>1</sup>	On-State	$V_{GS} = -4.5V, I_D = -5A$	P-Ch		44	60	
		$V_{GS} = 10V, I_D = 7A$	N-Ch		14	21	
		$V_{GS} = -10V, I_D = -6A$	P-Ch		28	35	
		$V_{DS} = 10V, I_D = 5A$	N-Ch		8		S
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = -10V, I_D = -5A$	P-Ch		7		

**DYNAMIC**

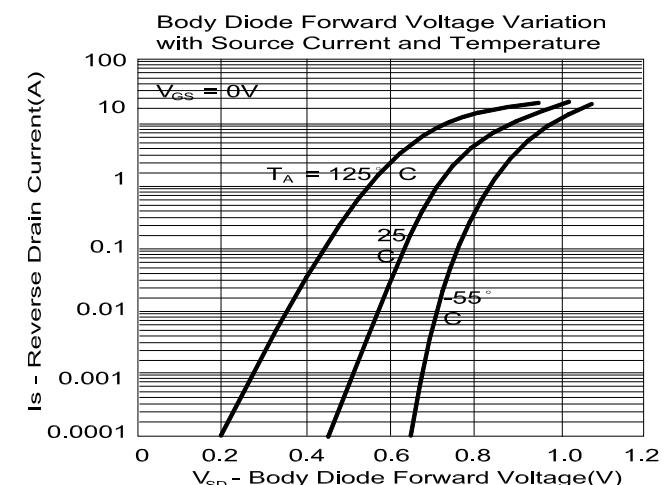
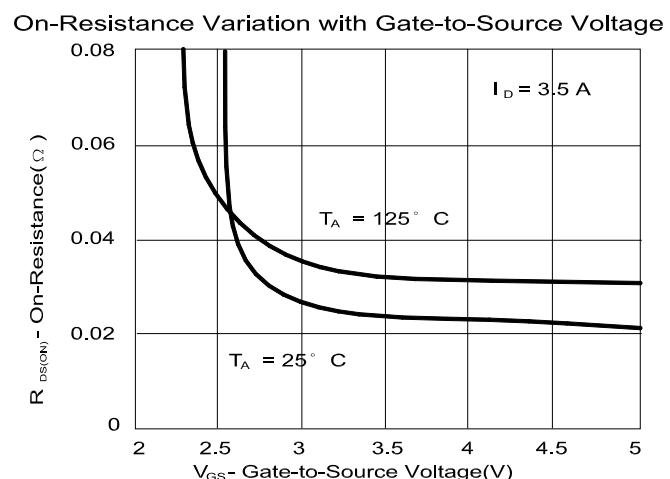
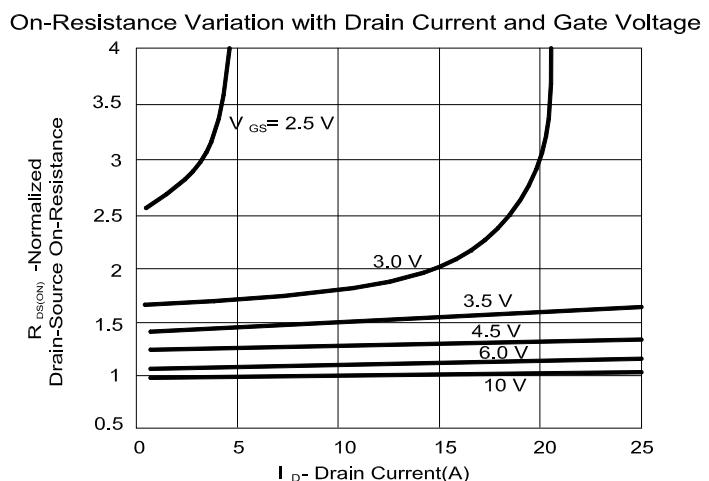
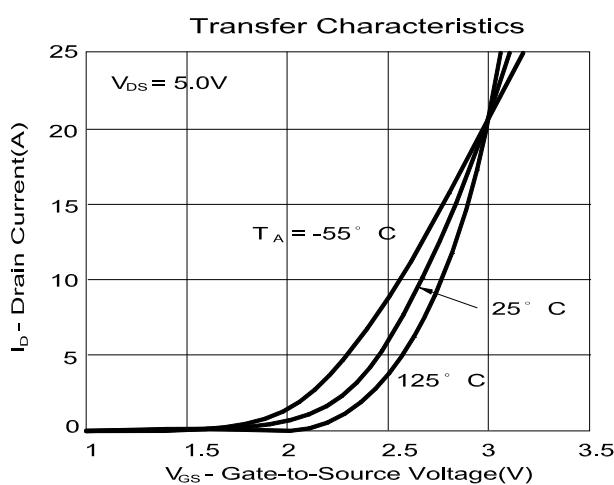
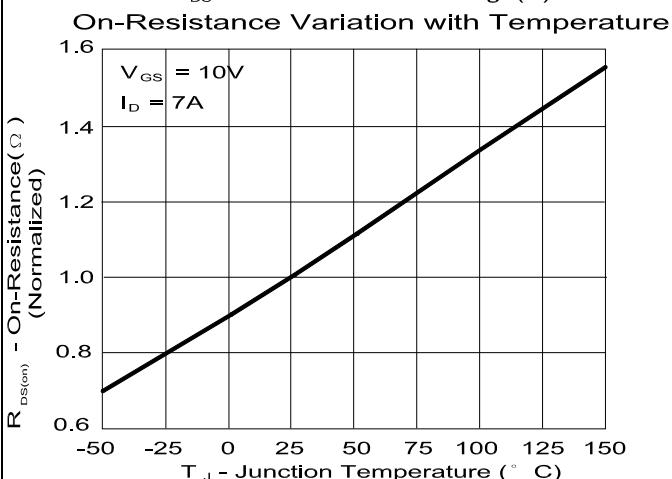
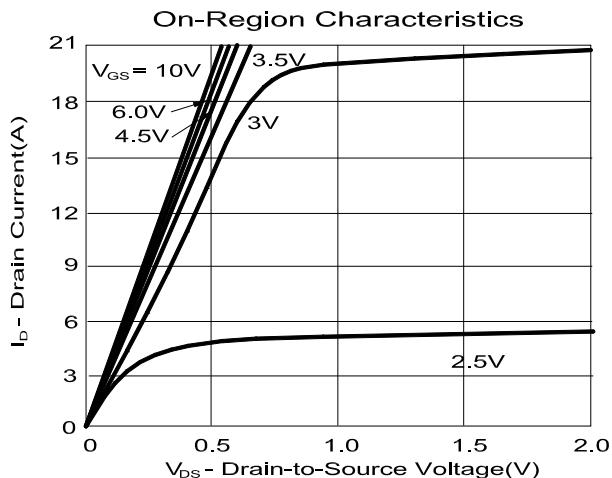
Input Capacitance	$C_{iss}$	N-Channel $V_{GS} = 0V, V_{DS} = 10V, f = 1MHz$ P-Channel $V_{GS} = 0V, V_{DS} = -10V, f = 1MHz$	N-Ch		1700		$pF$
Output Capacitance	$C_{oss}$		P-Ch		970		
Reverse Transfer Capacitance	$C_{rss}$		N-Ch		380		
Reverse Transfer Capacitance	$C_{rss}$		P-Ch		370		
Total Gate Charge <sup>2</sup>	$Q_g$	N-Channel $V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = 10V,$ $I_D = 6A$ P-Channel $V_{DS} = 0.5V_{(BR)DSS}, V_{GS} = -10V,$ $I_D = -5A$	N-Ch		260		$nc$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$		P-Ch		180		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		N-Ch		40		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$		P-Ch		28		

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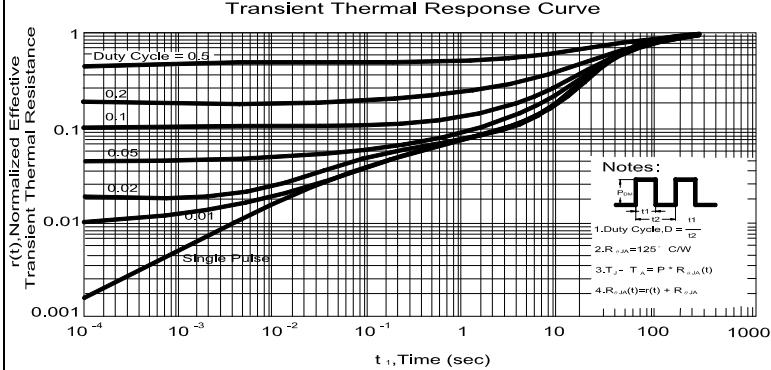
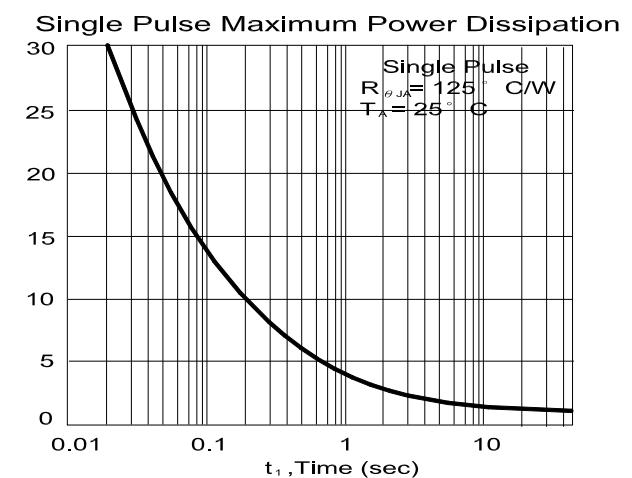
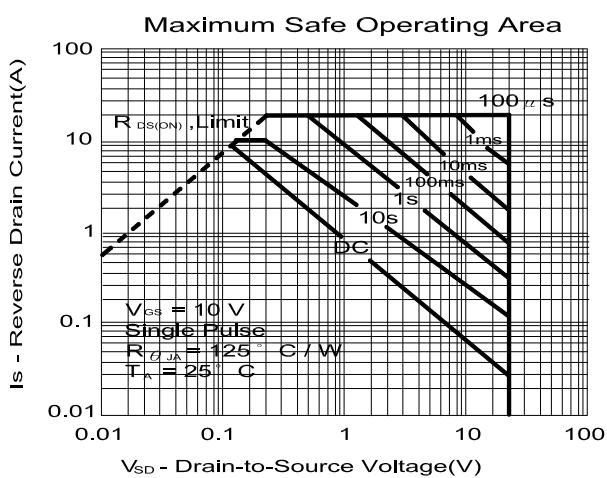
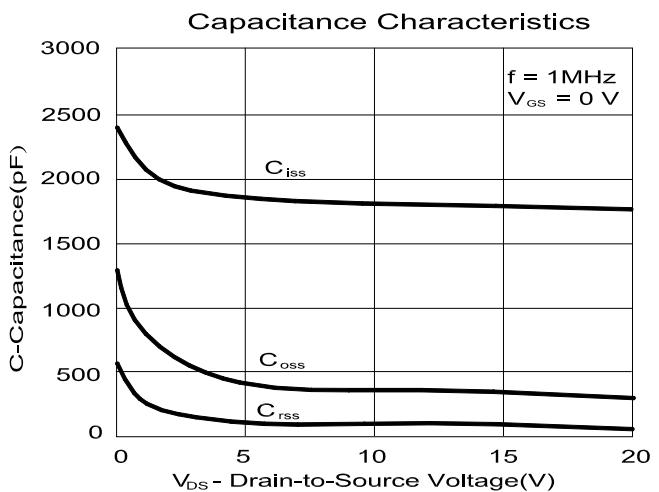
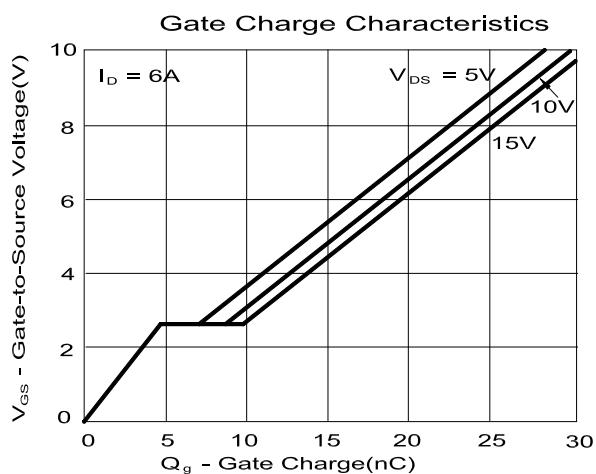
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$	N-Channel $V_{DS} = 15V$ $I_D \geq 1A, V_{GS} = 10V, R_{GEN} = 6\Omega$	N-Ch		20			
Rise Time <sup>2</sup>	$t_r$		N-Ch		20			
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$		N-Ch		10			
Fall Time <sup>2</sup>	$t_f$		P-Ch		17			
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ C</math>)</b>								
Continuous Current	$I_S$		N-Ch			3		
			P-Ch			-3		
Pulsed Current <sup>3</sup>	$I_{SM}$		N-Ch			6		A
			P-Ch			-6		
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 1A, V_{GS} = 0V$	N-Ch			1		
		$I_F = -1A, V_{GS} = 0V$	P-Ch			-1		V
Reverse Recovery Time	$t_{rr}$	$I_F = 5A, dI_F/dt = 100A / \mu S$	N-Ch		15.5			
		$I_F = -5A, dI_F/dt = 100A / \mu S$	P-Ch		15.5			
Reverse Recovery Charge	$Q_{rr}$		N-Ch		7.9			
			P-Ch		7.9			nC

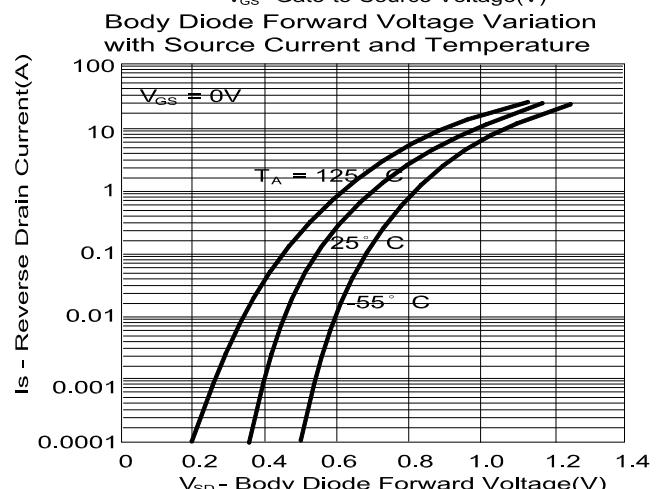
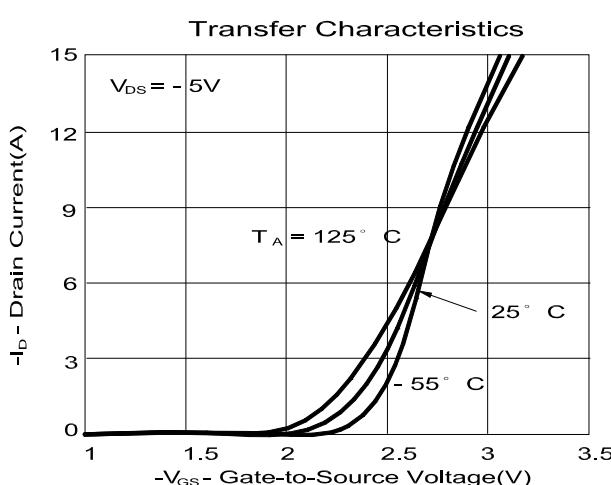
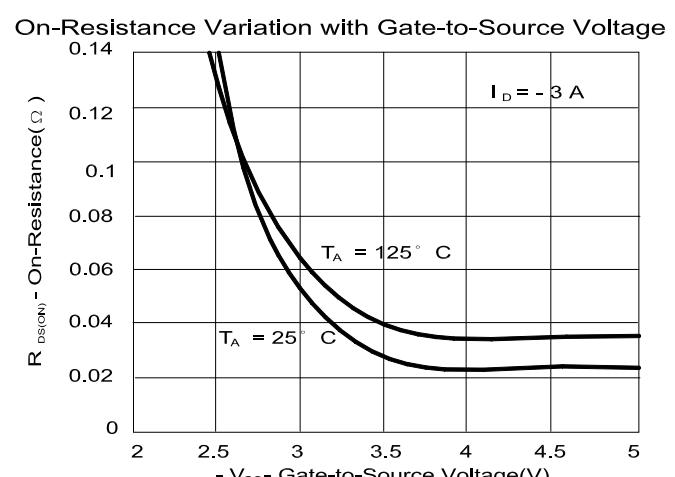
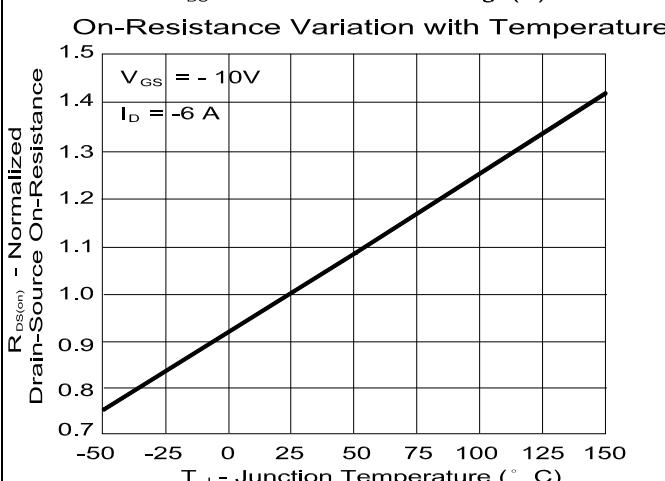
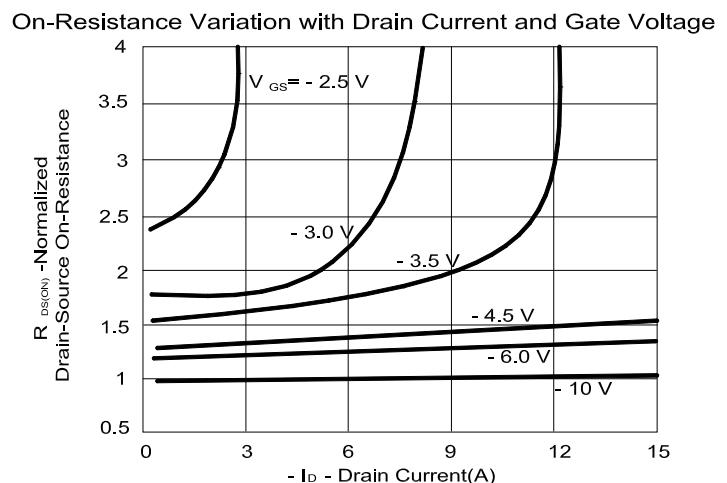
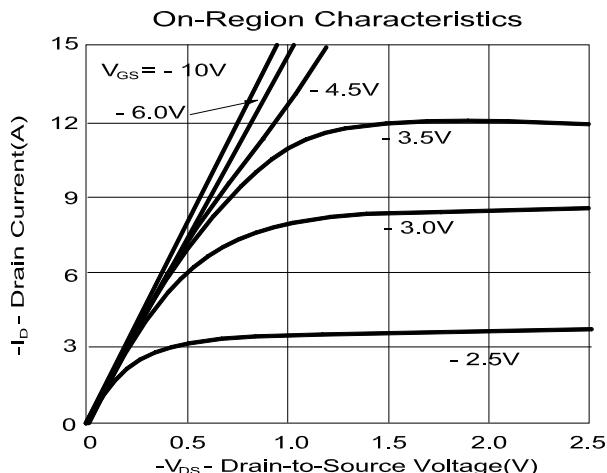
<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.<sup>3</sup>Pulse width limited by maximum junction temperature.**REMARK: THE PRODUCT MARKED WITH "P2103NV", DATE CODE or LOT #**

**N-CHANNEL**

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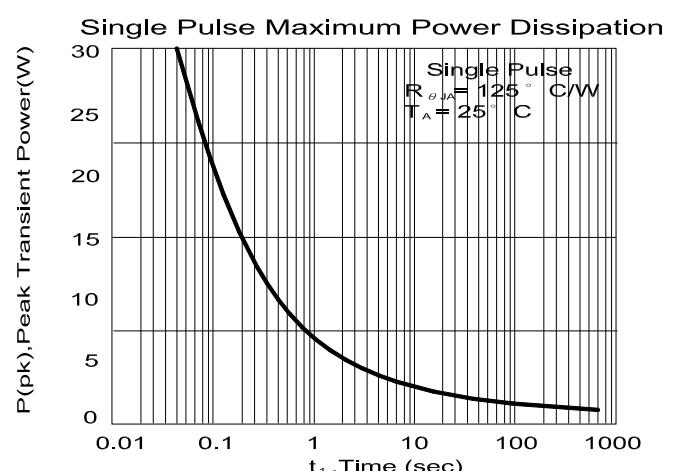
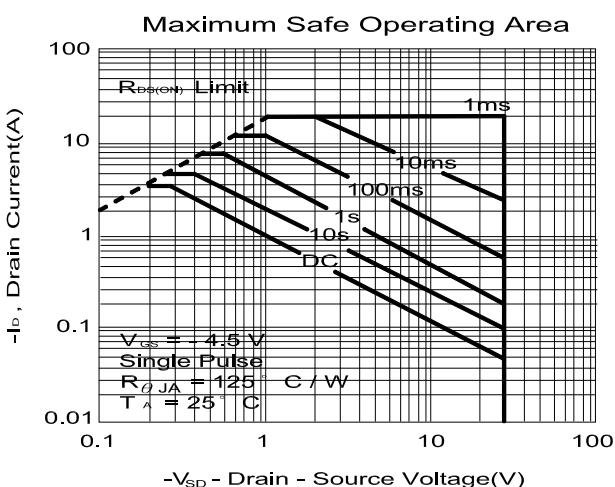
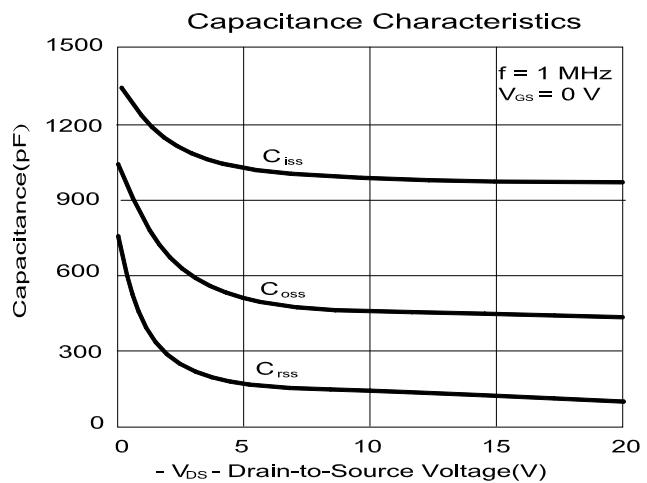
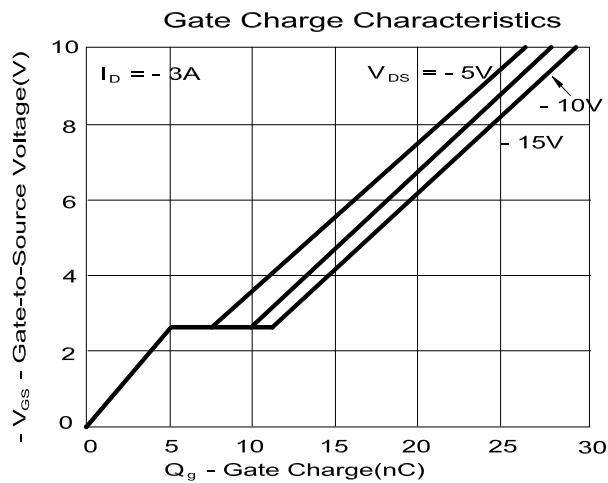
**P-CHANNEL**

**NIKO-SEM**

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Field Effect Transistor**

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## SOIC-8 (D) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.8	4.9	5.0	H	0.5	0.715	0.83
B	3.8	3.9	4.0	I	0.18	0.254	0.25
C	5.8	6.0	6.2	J		0.22	
D	0.38	0.445	0.51	K	0°	4°	8°
E		1.27		L			
F	1.35	1.55	1.75	M			
G	0.1	0.175	0.25	N			

